2SC4656

Silicon NPN epitaxial planar type



 (Common base, input open circuited)
 Image: Common base, input open circuited

 Note)
 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

Cob

 $V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$

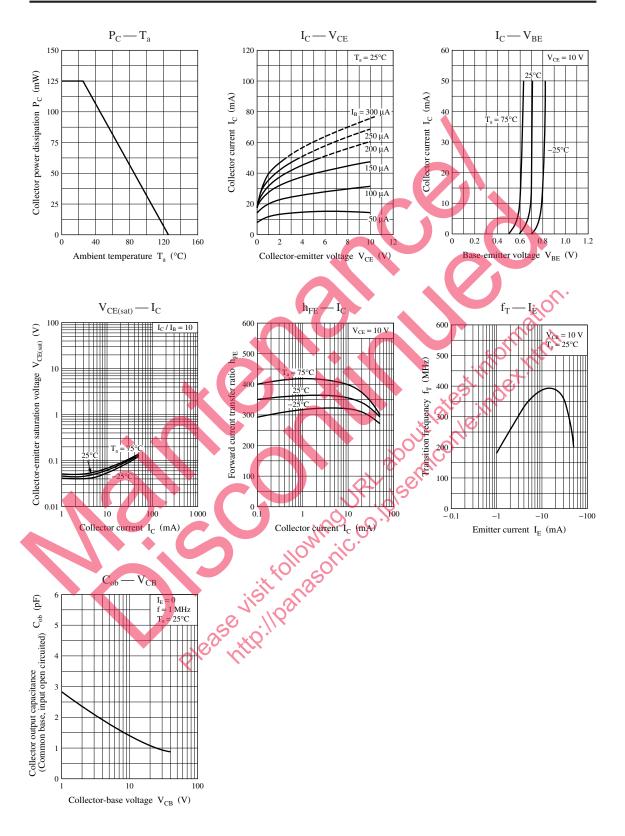
2. *: Rank classification

Collector output capacitance

Rank	Q	R
h _{FE}	200 to 400	250 to 500

pF

1.5



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